

<b>Notice of References Cited</b>		Application/Control No. 10/051,774	Applicant(s)/Patent Under Reexamination HSU ET AL.
		Examiner JOSEPH T. PHAN	Art Unit 2614

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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